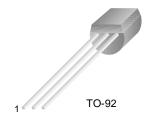


## **BF199**

### **NPN RF Transistor**



1. Collector 2. Emitter 3. Base

# **Absolute Maximum Ratings\*** $T_C=25$ °C unless otherwise noted

Symbol	Parameter	Value	Units
V <sub>CEO</sub>	Collector-Emitter Voltage	25	V
V <sub>CBO</sub>	Collector-Base Voltage	40	V
V <sub>EBO</sub>	Emitter-Base Voltage	4.0	V
I <sub>C</sub>	Collector Current - Continuous	50	mA
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	- 55 ~ 150	°C

<sup>\*</sup> These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

# Electrical Characteristics $T_C=25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Condition	Min.	Max.	Units	
Off Charact	eristics	•		•		
V <sub>(BR)CEO</sub>	Collector-Emitter Breakdown Voltage *	$I_C = 1.0 \text{mA}, I_B = 0$	25		V	
V <sub>(BR)CBO</sub>	Collector-Base BreakdownVoltage	$I_C = 100\mu A, I_E = 0$	40		V	
V <sub>(BR)EBO</sub>	Emitter-Base Breakdown Voltage	$I_E = 10\mu A, I_C = 0$	4.0		V	
I <sub>CES</sub>	Collector Cut-off Current	$V_{CE} = 30V, I_{E} = 0$		50	nA	
On Characteristics						
h <sub>FE</sub>	DC Current Gain	I <sub>C</sub> = 7.0mA, V <sub>CE</sub> = 10V	38			
V <sub>CE</sub> (sat)	Collector-Emitter Saturation Voltage	I <sub>C</sub> = 10mA, I <sub>B</sub> = 5.0mA		0.2	V	
V <sub>BE</sub> (sat)	Base-Emitter Saturation Voltage	I <sub>C</sub> = 10mA, I <sub>B</sub> = 5.0mA		0.92	V	
V <sub>BE</sub> (on)	Base-Emitter On Voltage	I <sub>C</sub> = 7.0mA, V <sub>CE</sub> = 10V		0.925	V	
Small Signa	I Characteristics					
f <sub>T</sub>	Current gain Bandwidth Product	$I_C = 7.0 \text{mA}, V_{CE} = 10 \text{V},$ f = 100 MHz		1100	MHz	
C <sub>re</sub>	Common-Emitter Ruerse Transfer Capacitance	$V_{CB} = 10V, I_{E} = 0, f = 1.0MHz$		0.4	pF	

<sup>\*</sup> Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2.0%

## Thermal Characteristics $T_A=25^{\circ}C$ unless otherwise noted

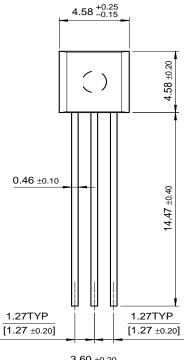
Symbol	Parameter	Max.	Units
P <sub>D</sub>	Total Device Dissipation	350	mW
	Derate above 25°C	2.8	mW/°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case	125	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	357	°C/W

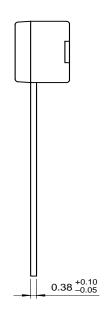
These ratings are based on a maximum junction temperature of 150 degrees C.
 These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations

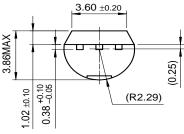
# **Package Dimensions**

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# TO-92







Dimensions in Millimeters

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	EnSigna™	I <sup>2</sup> C™	OCX™	RapidConfigure™	UHC™
	Across the board.	Around the world.™	OCXPro™	RapidConnect™	UltraFET <sup>®</sup>
The Power Franchise™		OPTOLOGIC <sup>®</sup>	SILENT SWITCHER®	VCX™	
	Programmable Ac	ctive Droop™	OPTOPLANAR™	SMART START™	

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